

STF24N60M2, STFI24N60M2

N-channel 600 V, 0.168 Ω typ., 18 A MDmesh II Plus™ low Q_g Power MOSFET in TO-220FP and I²PAKFP packages

Datasheet - production data

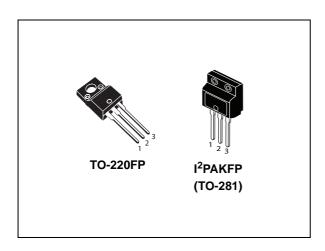
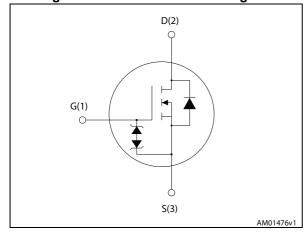


Figure 1. Internal schematic diagram



Features

Order codes	V _{DS} @ T _{Jmax}	R _{DS(on)} max	I _D
STF24N60M2	650 V	0.19 Ω	18 A
STFI24N60M2	000 V	0.10 22	10 /

- · Extremely low gate charge
- Lower R_{DS(on)} x area vs previous generation
- · Low gate input resistance
- 100% avalanche tested
- · Zener-protected

Applications

- Switching applications
- LLC converters, resonant converters

Description

These devices are N-channel Power MOSFETs developed using a new generation of MDmesh $^{\mathsf{TM}}$ technology: MDmesh II Plus $^{\mathsf{TM}}$ low \mathbf{Q}_g . These revolutionary Power MOSFETs associate a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. They are therefore suitable for the most demanding high efficiency converters.

Table 1. Device summary

Order codes	Marking	Package	Packaging
STF24N60M2	24N60M2	TO-220FP	Tube
STFI24N60M2	24INOUIVI2	I ² PAKFP (TO-281)	rube

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1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{GS}	Gate-source voltage	± 25	V
I _D	Drain current (continuous) at T _C = 25 °C	18 ⁽¹⁾	Α
I _D	Drain current (continuous) at T _C = 100 °C	12 ⁽¹⁾	Α
I _{DM} ⁽²⁾	Drain current (pulsed)	72 ⁽¹⁾	Α
P _{TOT}	Total dissipation at T _C = 25 °C	30	W
dv/dt (3)	Peak diode recovery voltage slope	15	V/ns
dv/dt ⁽⁴⁾	MOSFET dv/dt ruggedness	50	V/ns
V _{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s; Tc = 25 °C)	2500	V
T _{stg}	Storage temperature	- 55 to 150	°C
T _j	Max. operating junction temperature	- 33 to 130	O

- 1. Limited by maximum junction temperature.
- 2. Pulse width limited by safe operating area.
- 3. $I_{SD} \leq$ 18 A, di/dt \leq 400 A/ μ s; $V_{DS peak} < V_{(BR)DSS}, V_{DD}$ = 400 V.
- 4. $V_{DS} \le 480 \text{ V}$

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case max	4.17	°C/W
R _{thj-amb}	Thermal resistance junction-ambient max	62.5	°C/W

Table 4. Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AR}	Avalanche current, repetetive or not repetetive (pulse width limited by T_{jmax})	3.5	А
E _{AS}	Single pulse avalanche energy (starting T_j =25°C, I_D = I_{AR} ; V_{DD} =50)	180	mJ

2 Electrical characteristics

(T_C = 25 °C unless otherwise specified)

Table 5. On /off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$V_{GS} = 0, I_D = 1 \text{ mA}$	600			٧
	Zero gate voltage	$V_{GS} = 0, V_{DS} = 600 \text{ V}$			1	μΑ
I _{DSS}		$V_{GS} = 0,$ $V_{DS} = 600 \text{ V}, T_{C} = 125 \text{ °C}$			100	μΑ
I _{GSS}	Gate-body leakage current	$V_{DS} = 0, V_{GS} = \pm 25 \text{ V}$			±10	μΑ
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2	3	4	V
R _{DS(on)}	Static drain-source on- resistance	V _{GS} = 10 V, I _D = 9 A		0.168	0.19	Ω

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss}	Input capacitance		-	1060	-	pF
C _{oss}	Output capacitance	V _{DS} = 100 V, f = 1 MHz,	-	55	-	pF
C _{rss}	Reverse transfer capacitance	$V_{GS} = 0$	-	2.2	-	pF
Coss eq. (1)	Equivalent output capacitance	$V_{DS} = 0$ to 480 V, $V_{GS} = 0$	-	258	-	pF
R _G	Intrinsic gate resistance	f = 1 MHz, I _D =0	-	7	-	Ω
Qg	Total gate charge	V _{DD} = 480 V, I _D = 18 A,	-	29	-	nC
Q _{gs}	Gate-source charge	V _{GS} = 10 V	-	6	-	nC
Q _{gd}	Gate-drain charge	(see Figure 14)	-	12	-	nC

^{1.} $C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time		-	14	-	ns
t _r	Rise time	$V_{DD} = 300 \text{ V}, I_D = 9 \text{ A},$ $R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$	-	9	-	ns
t _{d(off)}	Turn-off delay time	(see <i>Figure 14</i> and <i>19</i>)	-	60	-	ns
t _f	Fall time		-	15	-	ns

Table 8. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD} ⁽¹⁾	Source-drain current		-		18	Α
I _{SDM} (1),(2)	Source-drain current (pulsed)		-		72	Α
V _{SD} (3)	Forward on voltage	I _{SD} = 18 A, V _{GS} = 0	-		1.6	V
t _{rr}	Reverse recovery time	40.4 400.4/	-	332		ns
Q _{rr}	Reverse recovery charge	I _{SD} = 18 A, di/dt = 100 A/μs V _{DD} = 60 V (see <i>Figure 16</i>)	-	4		μC
I _{RRM}	Reverse recovery current	Top of the top the top	-	24		Α
t _{rr}	Reverse recovery time	I _{SD} = 18 A, di/dt = 100 A/μs	-	450		ns
Q _{rr}	Reverse recovery charge	$V_{DD} = 60 \text{ V}, T_j = 150 ^{\circ}\text{C}$	-	5.5		μC
I _{RRM}	Reverse recovery current	(see Figure 16)	-	25		Α

^{1.} The value is rated according to $\rm R_{\mbox{\scriptsize thj-case}}$ and limited by package.

^{2.} Pulse width limited by safe operating area

^{3.} Pulsed: pulse duration = $300 \mu s$, duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for TO-220FP and Figure 3. Thermal impedance for TO-220FP and I²PAKFP I²PAKFP

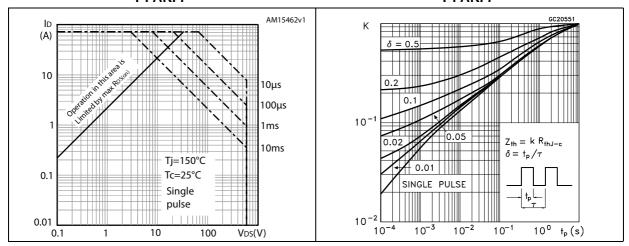


Figure 4. Output characteristics

Figure 5. Transfer characteristics

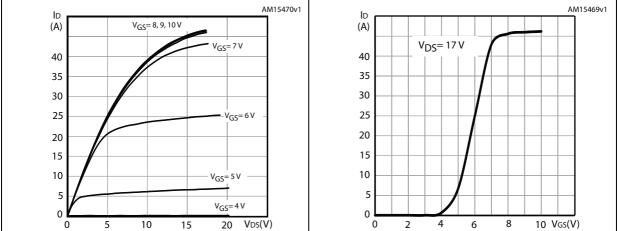
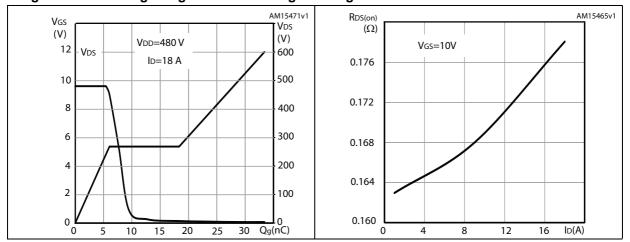


Figure 6. Gate charge vs gate-source voltage

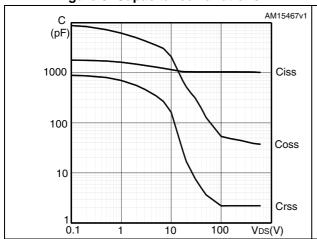
Figure 7. Static drain-source on-resistance



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Figure 8. Capacitance variations

Figure 9. Output capacitance stored energy



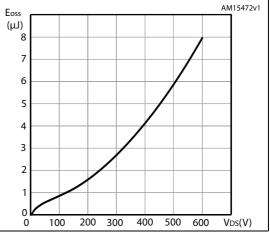
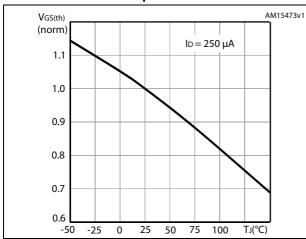


Figure 10. Normalized gate threshold voltage vs temperature

Figure 11. Normalized on-resistance vs temperature



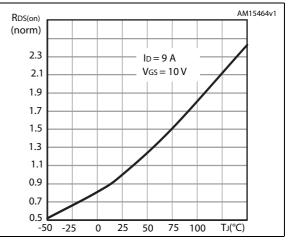
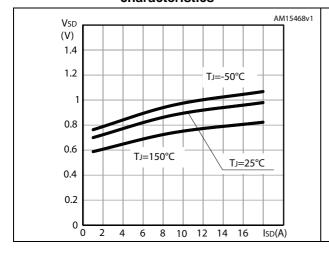
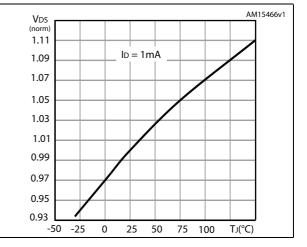


Figure 12. Source-drain diode forward characteristics

Figure 13. Normalized B_{VDSS} vs temperature





3 Test circuits

Figure 14. Switching times test circuit for resistive load

Figure 15. Gate charge test circuit

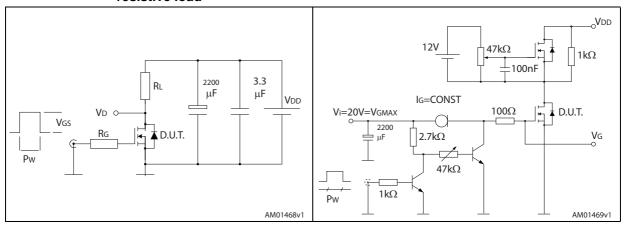


Figure 16. Test circuit for inductive load switching and diode recovery times

Figure 17. Unclamped inductive load test circuit

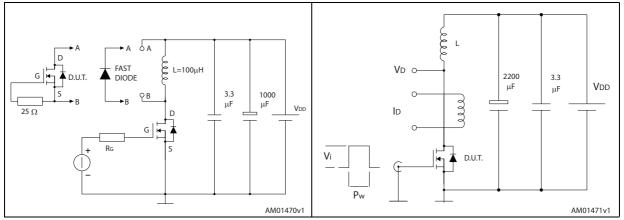
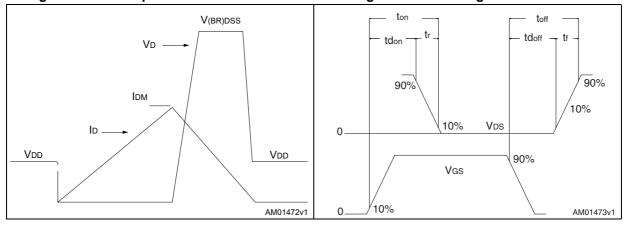


Figure 18. Unclamped inductive waveform

Figure 19. Switching time waveform



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4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK[®] is an ST trademark.



Table 9. TO-220FP mechanical data

Dim		mm	
Dim.	Min.	Тур.	Max.
А	4.4		4.6
В	2.5		2.7
D	2.5		2.75
Е	0.45		0.7
F	0.75		1
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.2
G1	2.4		2.7
Н	10		10.4
L2		16	
L3	28.6		30.6
L4	9.8		10.6
L5	2.9		3.6
L6	15.9		16.4
L7	9		9.3
Dia	3		3.2

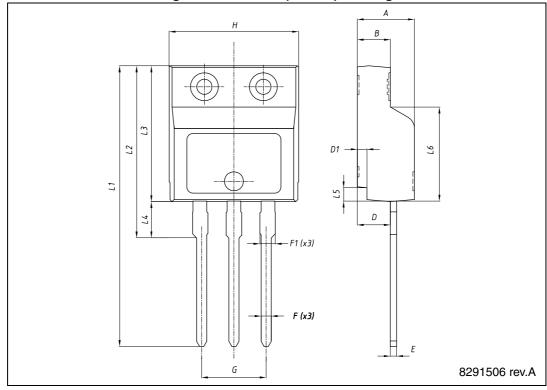
-*B*-Dia L6 *L2 L7* L3 F1 L4 *F2* Ε 7012510_Rev_K_B

Figure 20. TO-220FP drawing

Table 10. I²PAKFP (TO-281) mechanical data

Dim.		mm	
Dim.	Min.	Тур.	Max.
Α	4.40		4.60
В	2.50	_	2.70
D	2.50	_	2.75
D1	0.65		0.85
E	0.45		0.70
F	0.75		1.00
F1			1.20
G	4.95	-	5.20
Н	10.00	_	10.40
L1	21.00	_	23.00
L2	13.20	_	14.10
L3	10.55	1	10.85
L4	2.70	1	3.20
L5	0.85		1.25
L6	7.30		7.50

Figure 21. I²PAKFP (TO-281) drawing



5 Revision history

Table 11. Document revision history

Date	Revision	Changes
10-Dec-2012	1	First release.
20-Dec-2012	2	Added MOSFET dv/dt ruggedness in <i>Table 2: Absolute maximum ratings</i> .
14-Jan-2013	3	Modified: Figure 14, 15
28-May-2013	4	Modified: Figure 14, 15, 16 and 17Minor text changes

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